



Superior Technically. Supported Locally.



#### **CMI to Bowman**



Improved plated thru hole measurement using patented micro-resistance probes



Developed first slotted Coating Measurement XRF using PC detector



First to introduce point and shoot positioning, with laser focus



Improved the stability and extended the lifetime of micro spot X-ray tube



Launched Poly Capillary Optics XRF with Si Drift Detector • First and Only

First and Only
XRF manufacturer
to guarantee IPC
4552A compliance

New G Series
is the 1st
bottom-up XRF
with motorized
Z-axis

1987 > 1988 > 1990 > 1993 > 1995 > 2002 > 2009 > 2012 > 2014 > 2017 > 2018 > 2019

Introduced first handheld plated thru hole gauge using eddy current Launched first instrument operated by a stand-alone desktop computer Deployed Fundamental Parameters (FP) based coating measurement Launched XRF with Si PIN detector NPI Award: Bowman μ-spot Poly Capillary Optics XRF with SDD for smallest spot sizes Introduced world's smallest x-ray optics beam





### **BOWMAN Company Info**

- Founded in 2009 by Tom Leone and Jun Choi
- Main office: Schaumburg, Illinois (Chicago suburb)
- All products designed, engineered and manufactured in Schaumburg, USA
- Focus on XRF technology
- Sold more than 1000 units worldwide since 2013
- Worldwide supporting team, 200+
- All key managers and engineers are from CMI International (founded in 1985)



## Comprehensive XRF technology









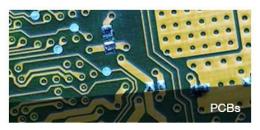




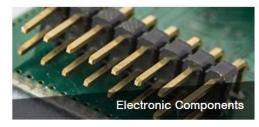


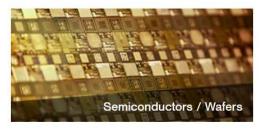


### **Major Applications**













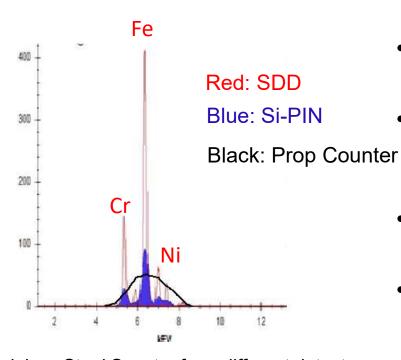








### Advantage of solid state detector



- Improved signal <u>sensitivity for</u> <u>low Z</u> elements
- Improved <u>detection limits</u>

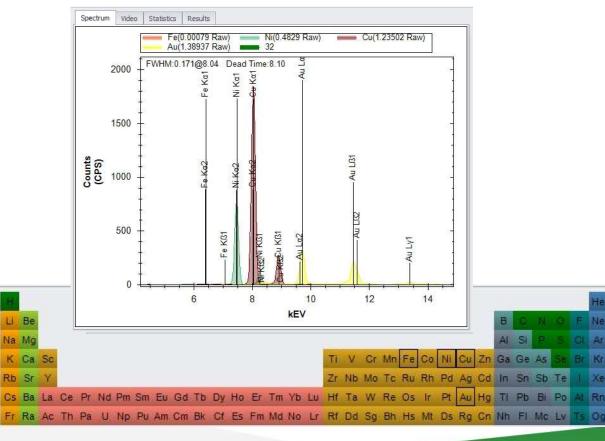
   down to Angstrom or ppm level
- <u>Separation</u> of overlapping elements
- Improved <u>stability</u> with minimal drift

304 Stainless Steel Spectra from different detectors

Bowman only uses solid state detectors (Si-PIN or SDD)



## Spectrum analysis





# The Bowman Advantage



#### Intuitive User Interface

It takes advanced design ... to make testing *simple!* Bowman XRF coating measurement systems are powered by leading edge software that combines intuitive, visual controls with time-saving shortcuts, flexible searchability and the industry's only true one-click report generator.

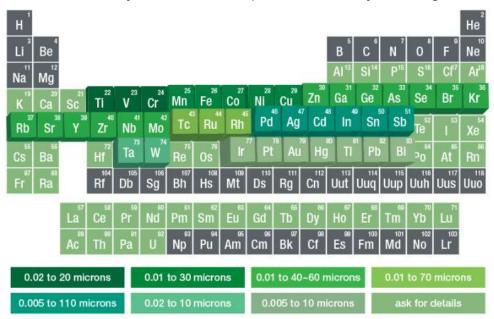
Users have unlimited ability to create new applications and format reports. All readings save to the database, and all user levels are password protected.



### The Bowman Advantage

#### **Unmatched Coating Thickness Range**

Bowman XRF measurement systems have a precision analysis range from Al 13 to U 92.





#### **B** series



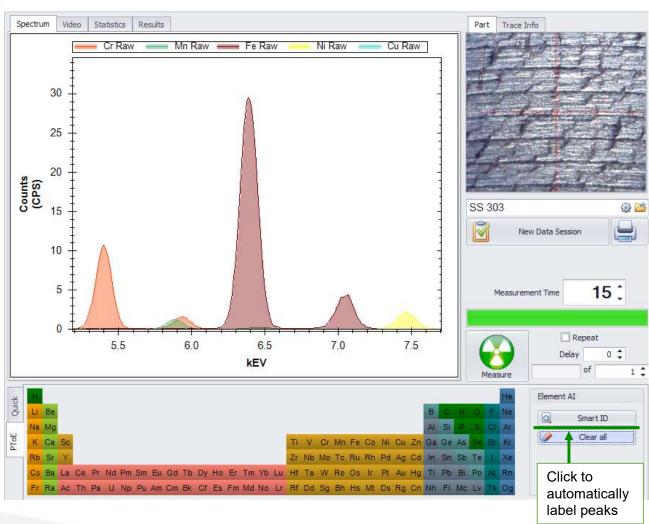
- The B Series represents the most basic topdown measurement configuration.
- Fixed base plate with slot for ease of manual sample positioning
- High resolution Silicon Drift Detector
- 20x micro viewing camera with 6x digital zoom
- Optional multi-collimators and variable focal depth
- Guaranteed to meet IPC-4552A, 4553A, 4554 and 4556
- ASTM B568, DIN 50987 and ISO 3497



- Automatically identify unknown elements
- Selectively identify individual elements



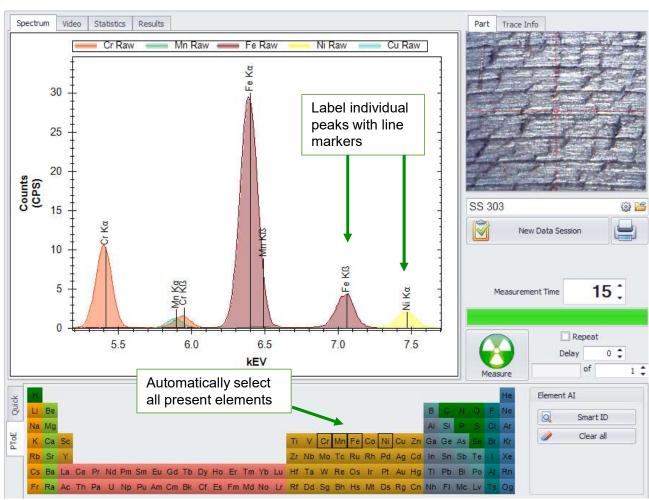
Automatically identify unknown elements based on peak position



Superior Technically. Supported Locally.



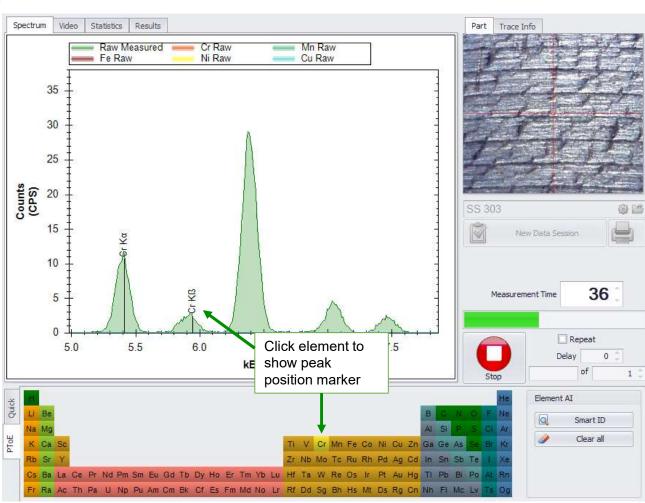
Automatically identify unknown elements based on peak position





# Manually identify individual elements by

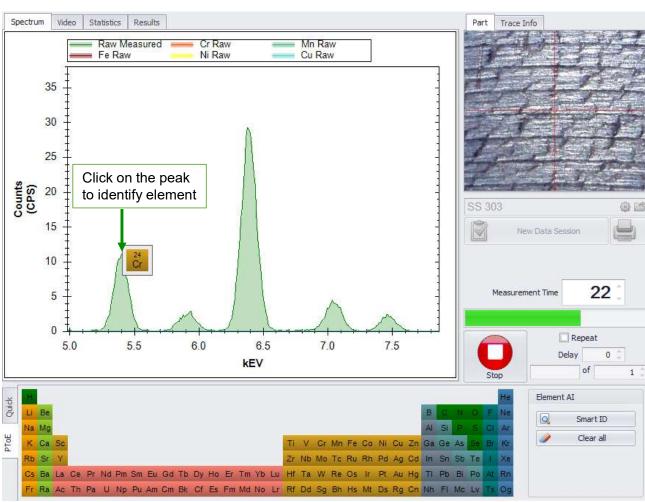
- Clicking on the element from the periodic table
- Hovering over elements will pull up temporary peak markers





# Manually identify individual elements by

 Clicking the peak on graph





# Materials Analysis(Spectrum Matching)

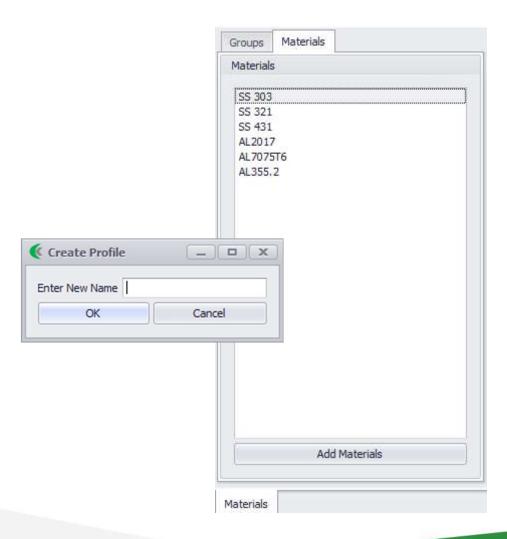
- Identify unknown material using spectrum library
  - Collect spectrum of known alloys
  - Fit unknown spectrum to library
  - Automatically call and analyze material in linked application



### **Materials Analysis**

#### **Materials Tab**

Add alloys

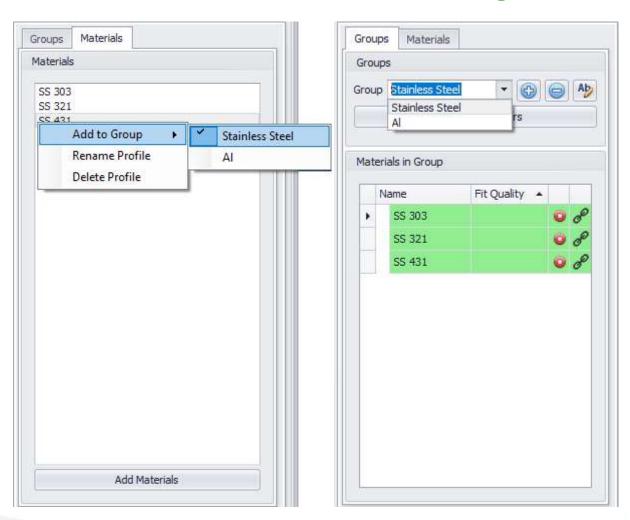




#### **Materials Tab**

 Create and sort into groups

### **Materials Analysis**

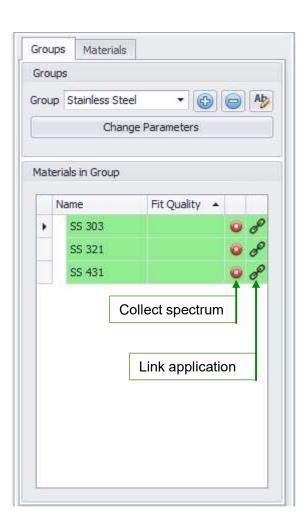




#### Materials Tab

- Collect spectrum
- Link materials to application

### **Materials Analysis**

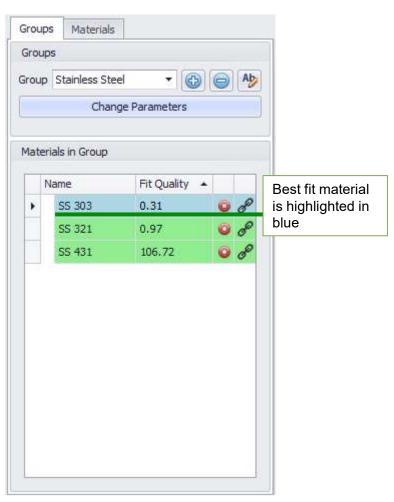




#### **Groups Tab**

- Measure unknown material
- Software fits unknown to materials library
- Smaller the value, the better the fit

### **Materials Analysis**

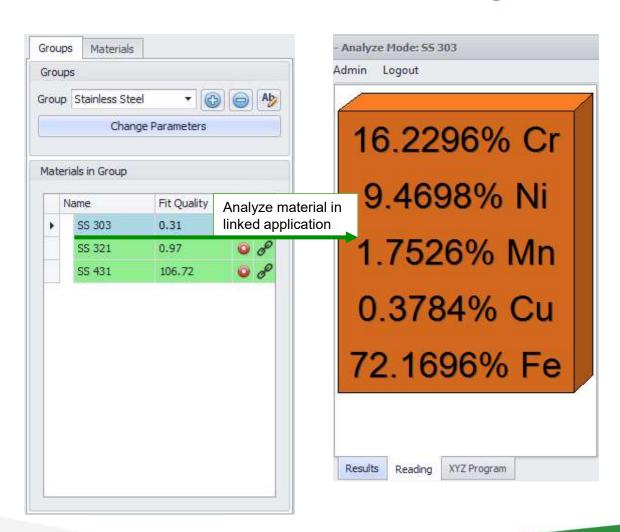




### **Materials Analysis**

#### **Groups Tab**

 Double click on the best fit to analyze material





### **Karat Analysis**

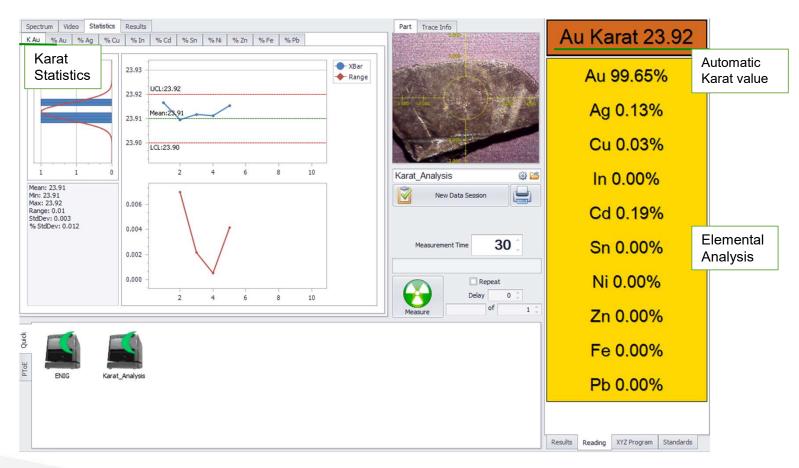
- Automatic Karat computation
- Up to 25 element analysis
- Optional displays

### Au Karat

Ag Au Bi Cd Co Cr Cu Fe In Ir Ni Os Pb Pd Pt Re Rh Ru Sn Ta Ti V W Zn Zr



### **Karat Analysis**





### **Karat Analysis**

#### Display options

Karat Analysis Options

✓ Display gold karat

Display full element names

Hide undetected elements

Au Karat 23.92

Au 99.65%

Ag 0.13%

Cu 0.03%

In 0.00%

Cd 0.19%

Sn 0.00%

Ni 0.00%

Zn 0.00%

Fe 0.00%

Pb 0.00%

Karat Analysis Options

✓ Display gold karat

✓ Display full element names

Hide undetected elements

Gold Karat 23.92

Gold 99.65%

Silver 0.13%

Copper 0.03%

Indium 0.00%

Cadmium 0.19%

Tin 0.00%

Nickel 0.00%

Zinc 0.00%

Iron 0.00%

Lead 0.00%

Karat Analysis Options

✓ Display gold karat

Display full element names

✓ Hide undetected elements

Gold Karat 23.92

Gold 99.65%

Silver 0.13%

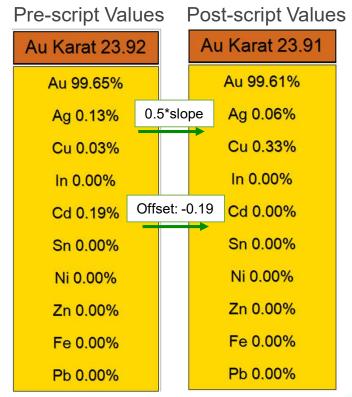
Copper 0.03%

Cadmium 0.19%



### **Post Analytical Script**

- Apply corrections to software calculated results:
  - Normalization the composition of selective elements
  - Slope correction
  - Offsets
  - Inhibit elements, etc
- Software will display postscript corrected values

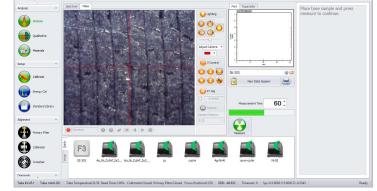




**Enable Base** 

correction

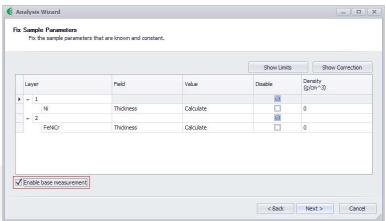
#### **Base Correction**

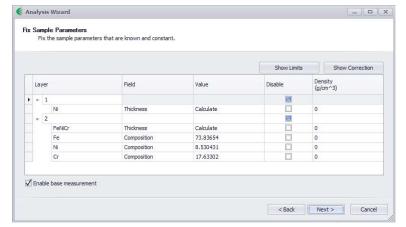


Measure Sample Base Material



Composition Values calculate automatically





Superior Technically. Supported Locally.



#### Reference standards



Superior Technically. Supported Locally.



#### ISO 17025:2017 Accreditation & Scope



#### CERTIFICATE OF ACCREDITATION

**ANSI National Accreditation Board** 

11617 Coldwater Road, Fort Wayne, IN 46845 USA

This is to certify that

**Bowman Analytics, Inc.** 

1125 Remington Road Schaumburg, IL 60173

has been assessed by ANAB and meets the requirements of international standard

ISO/IEC 17025:2017

and national standard

ANSI/NCSL Z540-1-1994 (R2002)

while demonstrating technical competence in the field of

#### CALIBRATION

Refer to the accompanying Scope of Accreditation for information regarding the types of activities to which this accreditation applies

> L2213 Certificate Number





This laboratory is accredited in accordance with the recognized International Standard ISO/IEC 17025:2017. This accreditation demonstrates technical competence for a defined scope and the operation of a laboratory quality management system (refer to joint ISO-ILAC-IAF Communique dated April 2017).



SCOPE OF ACCREDITATION TO ISO/IEC 17025:2017 AND ANSI/NCSL Z540-1-1994 (R2002)

Bowman Analytics, Inc.

1125 Remington Road Schaumburg, IL 60173 Ron Wochinski 847-781-3523

#### CALIBRATION

Valid to: November 21, 2020

Certificate Number: L2213

Length - Dimensional Metrology

Parameter/Equipment	Range	Expanded Uncertainty of Measurement (+/-)	Reference Standard, Method, and/or Equipment
Coating Thickness Measuring – Equipment and Coating Thickness Standards	(0.1 to 3 000) µin	3.5% of reading	ASTM B568 (X-Ray)
	(100 to 2 000) μin	4.9% for Eddy Current	ASTM E376 (Eddy Current)
	(100 to 60 000) µin	6.2% for Magnetic Induction	ASTM B499 (Magnetic Induction)

#### Mass and Mass Related

Parameter/Equipment	Range	Expanded Uncertainty of Measurement (+/-) <sup>2</sup>	Reference Standard, Method, and/or Equipment
Composition - NiP	(1 to 99) wt%	0.62 %	ASTM B568 (X-Ray)
Composition - Alloy	(1 to 99) wt%	1.68 %	

Calibration and Measurement Capability (CMC) is expressed in terms of the measurement parameter, measurement range, expanded uncertainty of measurement and reference standard, method, and or equipment. The expanded uncertainty of measurement is expressed as the standard uncertainty of the measurement multiplied by a coverage factor of 2 (k=2), corresponding to a confidence level of approximately 95%.

- 1. On-site calibration service is available for this parameter, since on-site conditions are typically more variable than those in the laboratory, larger measurement
- uncertainties are expected on-site than what is reported on the accredited scope.
  Weight per centage applied unless otherwise indicated.
  This scope is formatted as part of a single document including Certificate of Accreditation No. L2213.





### Coming soon

#### **New Bowman Standards**

- New standard model allows stacking multiple standards flat and evenly for custom applications.
- Total thickness: 8mil
- Shorter lead time: 2-3 weeks for most standards.





### Coming soon

#### **Bowman Infinite Card**

- Will include 15 elements in a compact design for quick spectrum reference.
- 2mm total thickness, 2" x 3" (H x L)
- Low profile design to be used in both collimated and optics systems.
- Al, Ti, Cr, Fe, Ni, Cu, Zn, W, Mo, Pd, Ag, Cd, Sn, An, Pb
- Upcoming software version will allow the user to collect reference element checkpoints and extrapolate the INFs in between







### What are X-rays

- X-rays are a type of radiation called electromagnetic waves.
- Invisible lights have a wavelength ranging from 0.03 to 3 nanometers.



### The Electromagnetic Spectrum

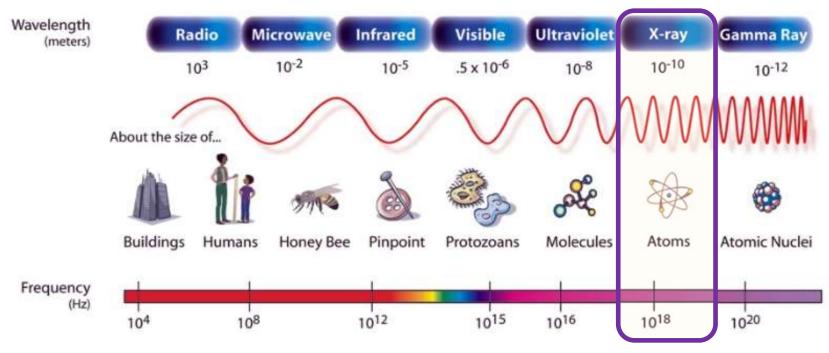
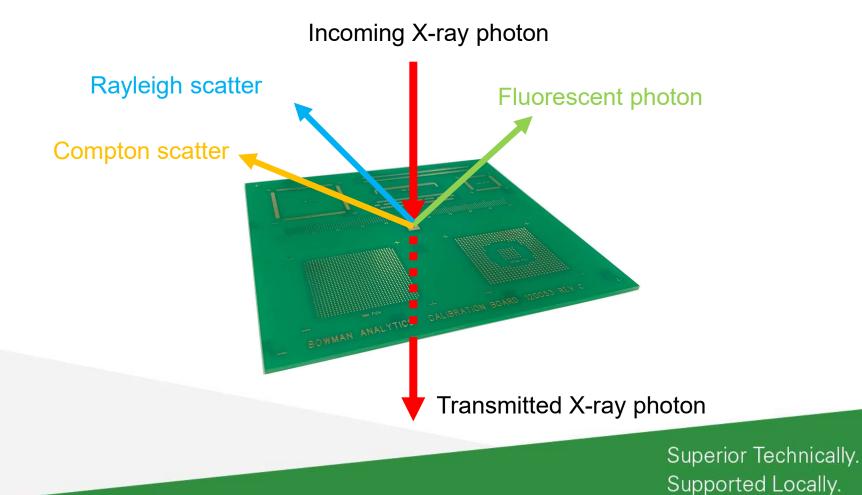


Image is from Pinterest.com

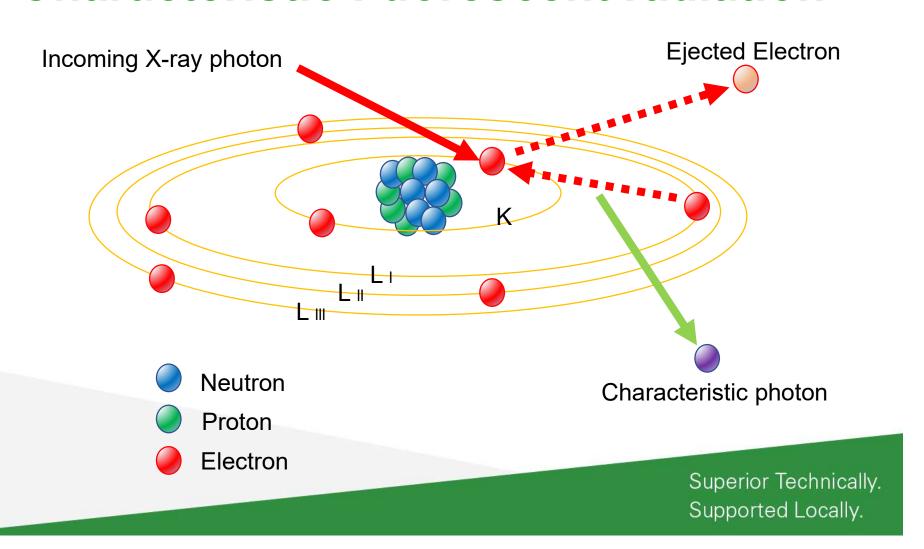


### Three main interactions of X-rays with matter



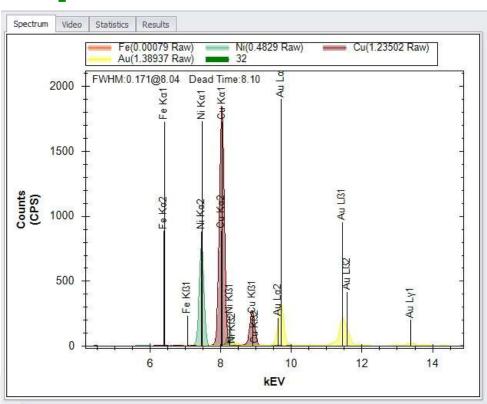


#### Characteristic fluorescent radiation



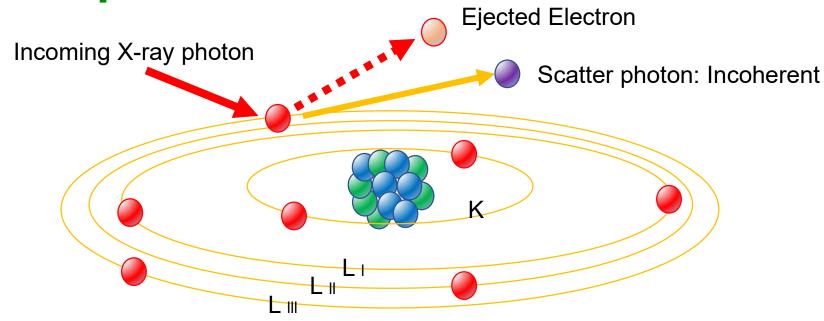


### Sample spectrum





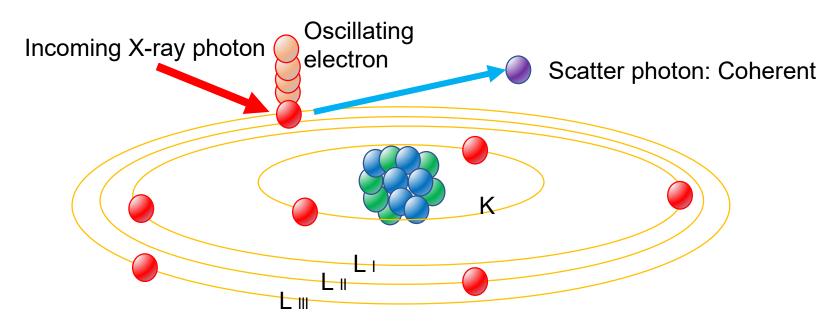
**Compton scatter** 



- Neutron
- Proton
- Electron



### Rayleigh scatter









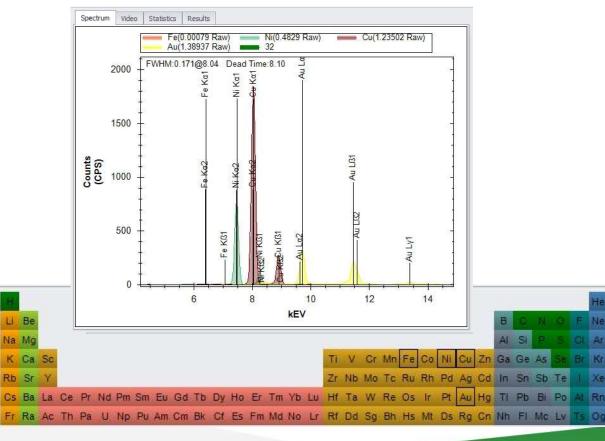


### **Key components**

- X-ray Tube
- Primary Filters and Shutter
- Collimators
- Camera
- Detector and Digital Pulse Processor
- PC



## Spectrum analysis







Superior Technically.
Supported Locally.

